

# 1A01K170K

## Silicon Carbide Power MOSFET N-Channel Enhancement Mode

$V_{DS}$	=	1700 V
$R_{DS(on)}$	=	1.0 $\Omega$
$I_{DS@25^\circ C}$	=	5.0 A

### Features

- High Blocking Voltage with low On-Resistance
- High Speed Switching with Low Capacitances
- Easy to Parallel and Simple to Drive
- Ultra-low Drain-gate capacitance
- Avalanche Ruggedness

### Benefits

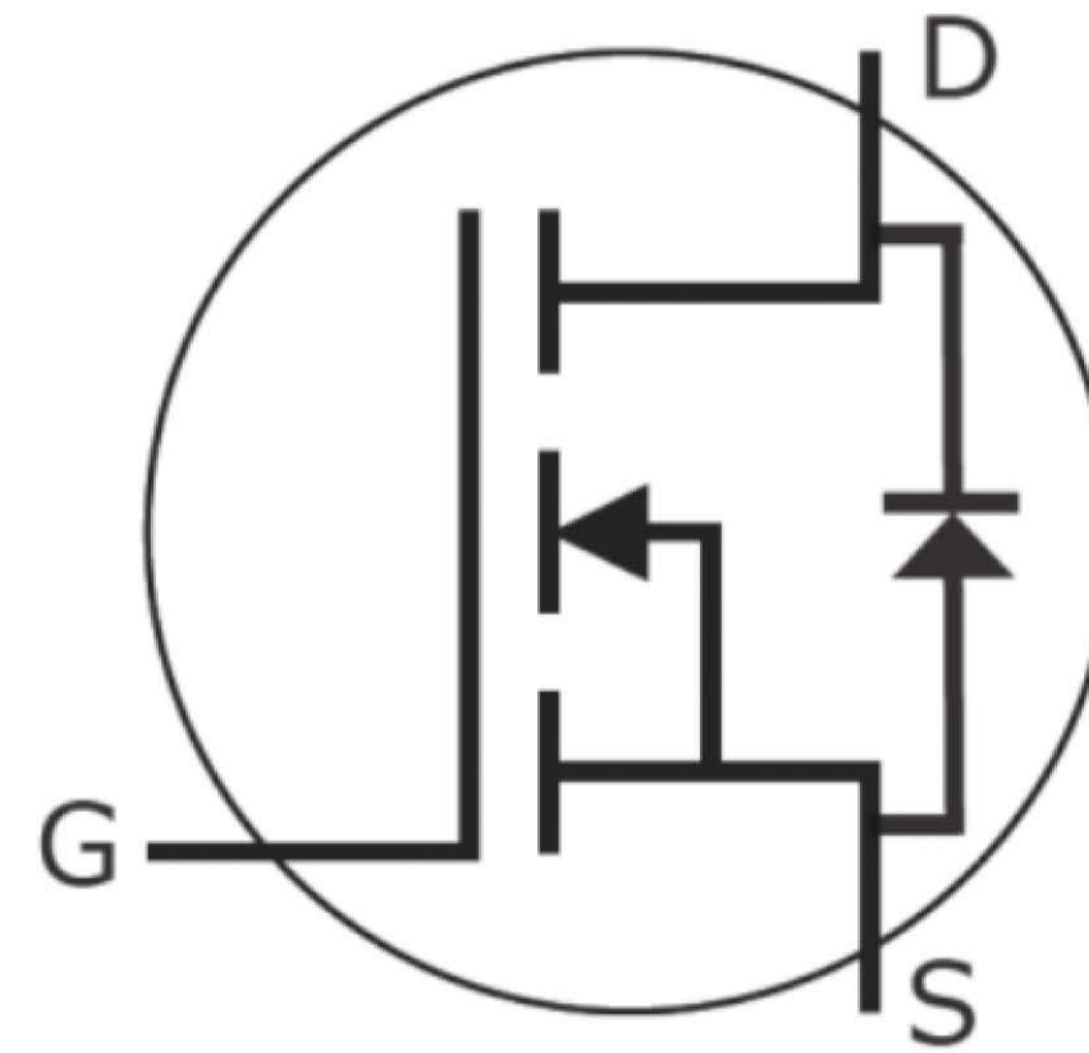
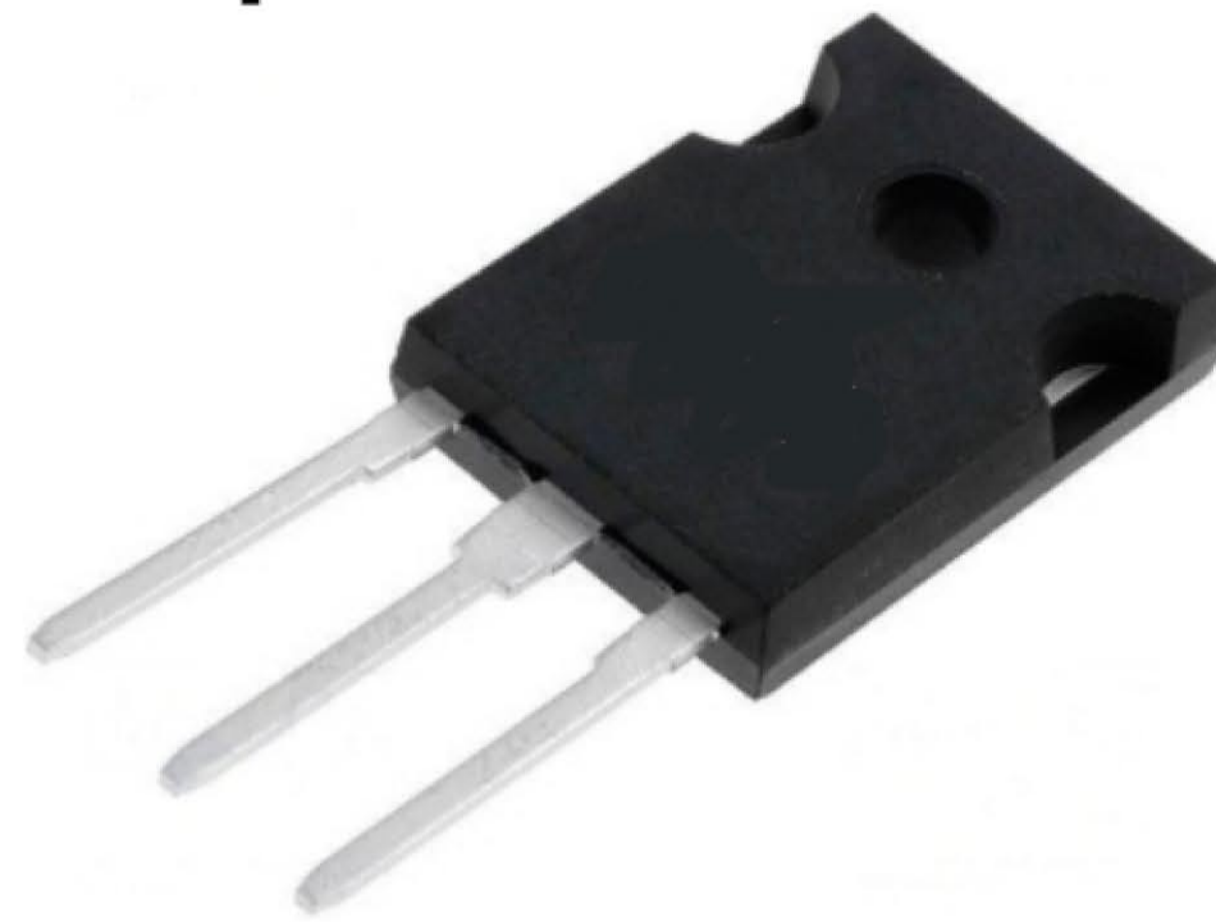
- Higher System Efficiency
- Reduced Cooling Requirements
- Increased System Reliability
- Increased System Switching Frequency

### Applications

- Auxiliary Power Supplies
- Switch Mode Power Supplies

- High-voltage Capacitive

### Chip Outline



Part Number	Package
1A01K170K	TO-247-3

### Maximum Ratings ( $T_C=25^\circ C$ unless otherwise specified)

Symb ol	Parameter	Value	Uni t	Test Conditions	Note
$V_{DSmax}$	Drain-Source Voltage	1700	V	$V_{GS}=0V, I_{DS}=100\mu A$	
$V_{GSmax}$	Gate-Source Voltage	-10/+25	V	Absolute maximum values	
$V_{GSop}$	Gate-Source Voltage	-5/+20	V	Recommended operational values	
$I_D$	Continuous Drain Current	5.0	A	$V_{GS}=20V, T_C=25^\circ C$	
		3.5	A	$V_{GS}=20V, T_C=100^\circ C$	
$I_{D(pulse)}$	Pulsed Drain Current	6.0	A	Pule width $t_p$ limited by $T_{jmax}$	
$P_D$	Power Dissipation	69	W	$T_C=25^\circ C, T_J=150^\circ C$	
$T_J, T_{ST}$	Operating Junction and Storag e Temperature	-55 to +150	$^\circ C$		
$T_L$	Solder Temperature	260	$^\circ C$	1.6mm(0.063") from case for 10s	

**Electrical Characteristics(T<sub>C</sub>=25°C unless otherwise specified)**

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions	Note
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	1700	/	/	V	V <sub>GS</sub> =0V, I <sub>DS</sub> =100μA	
V <sub>GS(th)</sub>	Gate Threshold Voltage	2.5	3.0	4.5	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>DS</sub> =1mA	
			2.2	/		V <sub>DS</sub> =V <sub>GS</sub> , I <sub>DS</sub> =1mA, T <sub>J</sub> =150°C	
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	/	1	100	μA	V <sub>DS</sub> =1700V, V <sub>GS</sub> =0V	
I <sub>GSS</sub>	Gate-Source Leakage Current	/		250	nA	V <sub>DS</sub> =0V, V <sub>GS</sub> =20V	
R <sub>DS(on)</sub>	Drain-Source On-State Resistance	/	1.0	1.3	Ω	V <sub>GS</sub> =20V, I <sub>D</sub> =2A	
		/	1.5			V <sub>GS</sub> =20V, I <sub>D</sub> =2A, T <sub>J</sub> =150°C	
g <sub>fs</sub>	Transconductance	/	1.15	/	S	V <sub>DS</sub> = 20 V, I <sub>D</sub> = 2 A	
		/	1.30	/		V <sub>DS</sub> =20V, I <sub>D</sub> = 2 A, T <sub>J</sub> = 150°C	
C <sub>iss</sub>	Input Capacitance	/	186	/	pF	V <sub>GS</sub> =0V V <sub>DS</sub> =1000V f=1MHz V <sub>AC</sub> =25mV	
C <sub>oss</sub>	Output Capacitance	/	12	/			
C <sub>rss</sub>	Reverse Transfer Capacitance	/	1.6	/			
E <sub>oss</sub>	C <sub>oss</sub> Stored Energy	/	6.2	/	μJ		
t <sub>don</sub>	Turn-On Delay Time	/	5.2	/	ns	V <sub>DS</sub> =1200V, V <sub>GS</sub> =-5V/20V I <sub>D</sub> =30A, R <sub>g</sub> =2.5Ω R <sub>L</sub> =600Ω (TO-247-3Package)	
t <sub>r</sub>	Rise Time	/	9.4	/			
t <sub>doff</sub>	Turn-Off Delay Time	/	13.2	/			
t <sub>f</sub>	Fall Time	/	22.0	/			
E <sub>ON</sub>	Turn-On Switching Energy	/	48	/	μJ	V <sub>DS</sub> =1200V, V <sub>GS</sub> =-5V/20V I <sub>D</sub> =2A, R <sub>g</sub> =2.5Ω, L=1500μH (TO-247-3Package)	
E <sub>OFF</sub>	Turn-Off Switching Energy	/	18	/			
R <sub>G</sub>	Internal Gate Resistance	/	22	/	Ω	f=1MHz open drain	
Q <sub>gs</sub>	Gate Charge Total	/	5.2	/	nC	V <sub>DS</sub> =1200V V <sub>GS</sub> =-5V/20V I <sub>D</sub> =2A	
Q <sub>gd</sub>	Gate to Source Charge	/	7.3	/			
Q <sub>g</sub>	Gate to Drain Charge	/	21.8	/			

**Reverse Diode Characteristics**

Symbol	Parameter	Typ.	Max.	Unit	Test Conditions	Note
V <sub>SD</sub>	Diode Forward Voltage	4.2		V	V <sub>GS</sub> =-5V, I <sub>F</sub> =1A	
		3.9			V <sub>GS</sub> =-5V, I <sub>F</sub> =1A, T <sub>J</sub> =150°C	
I <sub>s</sub>	Continuous Diode Forward Current		4.0	A	T <sub>C</sub> =25°C	
t <sub>rr</sub>	Reverse Recover time	25		ns	V <sub>GS</sub> =-5V, I <sub>SD</sub> =2A, V <sub>R</sub> =1200V	
Q <sub>rr</sub>	Reverse Recovery Charge	15		nC		
I <sub>rm</sub>	Peak Reverse Recovery Current	2.8		A		

### Reverse Diode Characteristics

Symbol	Parameter	Typ.	Max.	Unit	Test Conditions	Note
$R_{\theta JC}$	Thermal Resistance	1.8	2.0	$^{\circ}C/W$		

### Typical Performance

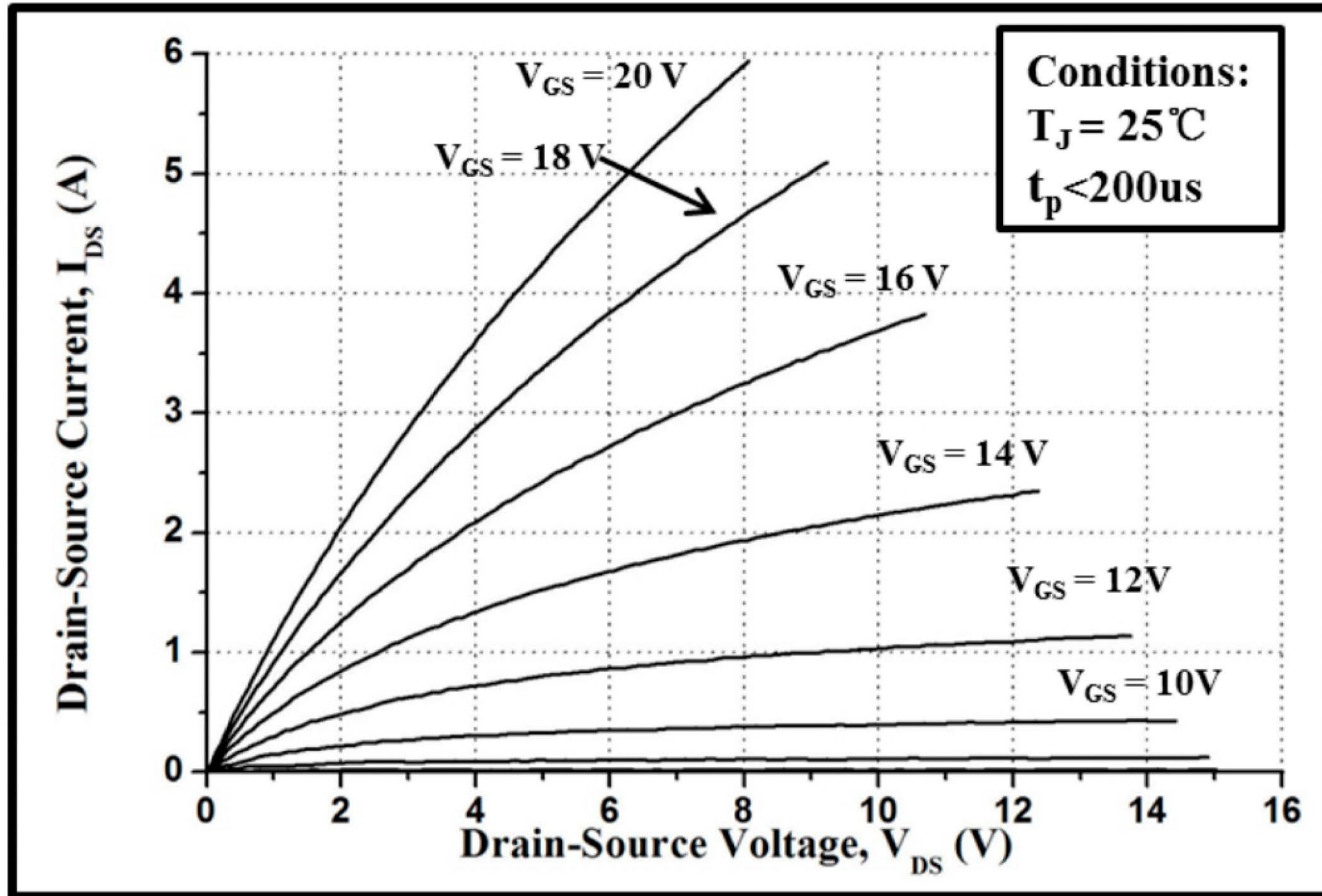


Figure 1. Typical Output Characteristics  $T_J = 25^{\circ}C$

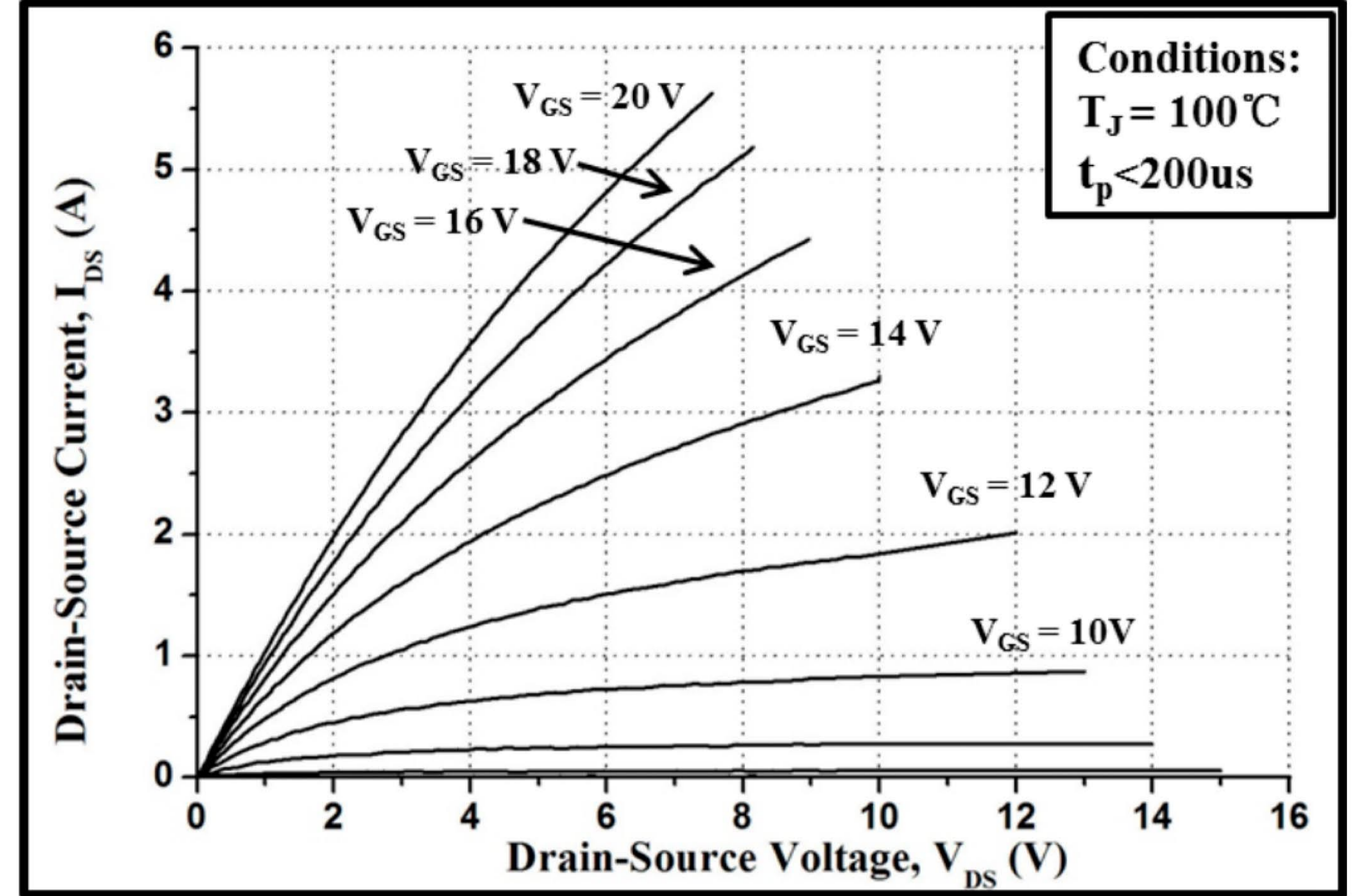


Figure 2. Typical Output Characteristics  $T_J = 100^{\circ}C$

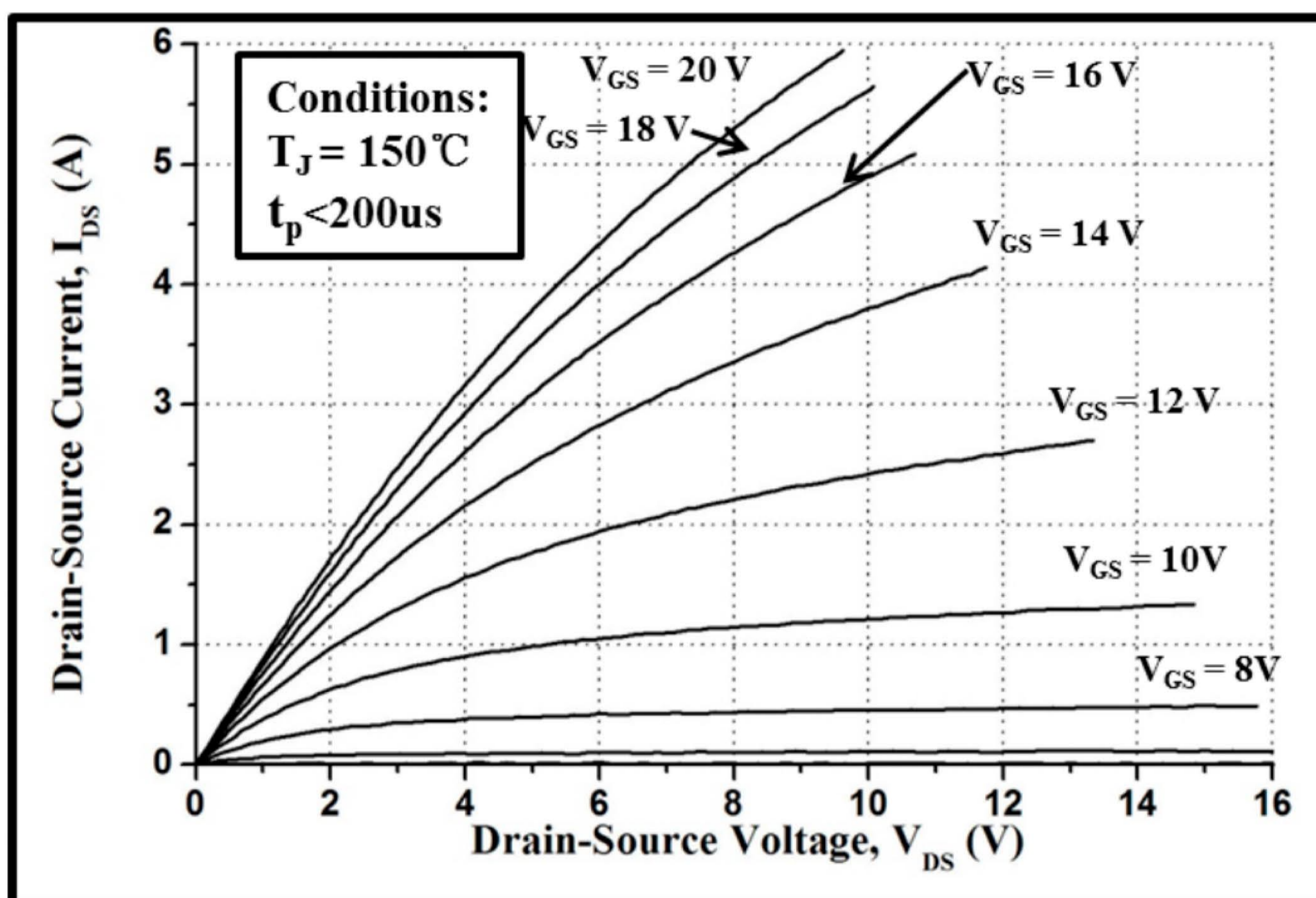


Figure 3. Typical Output Characteristics  $T_J = 150^{\circ}C$

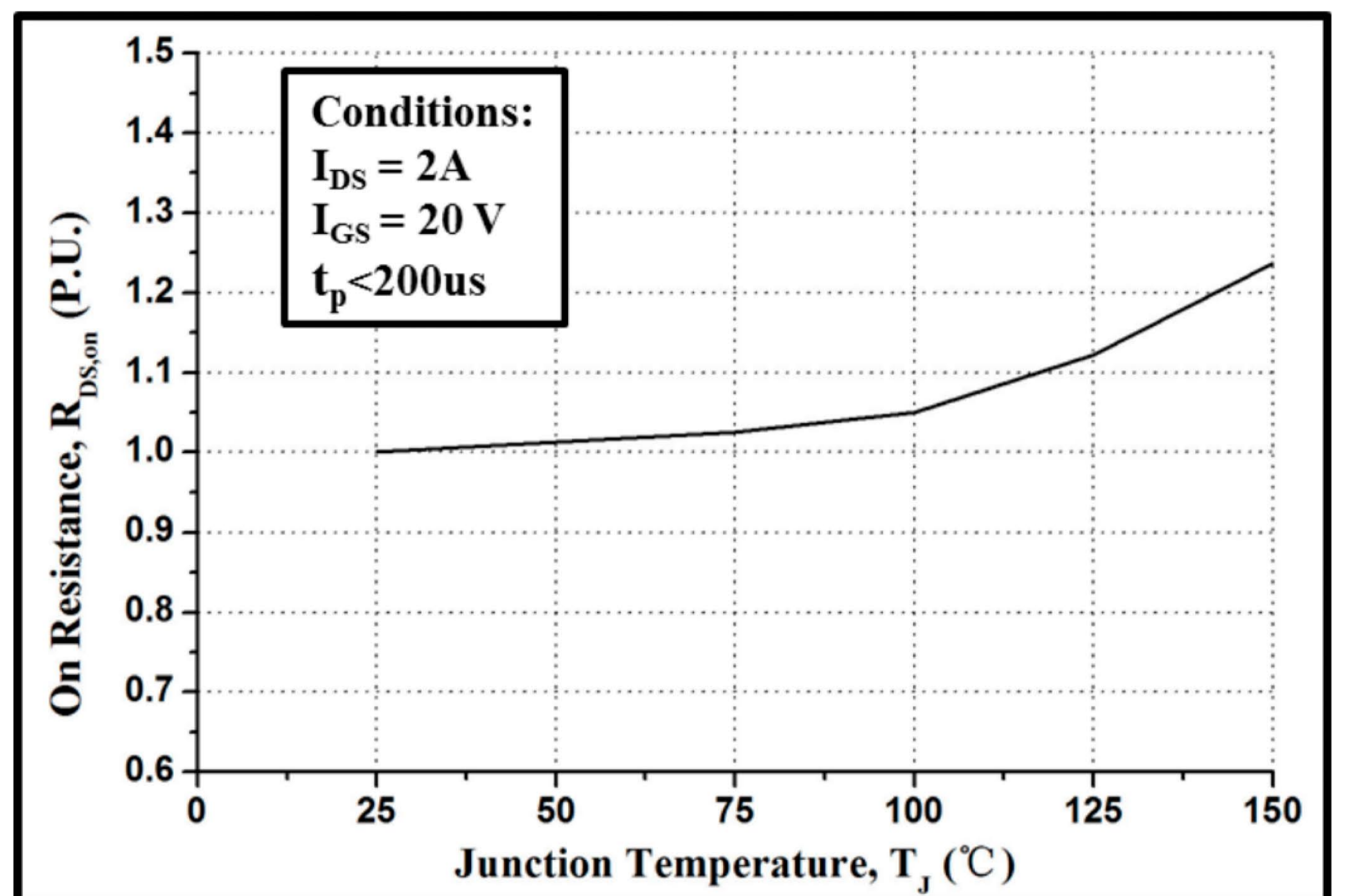


Figure 4. Normalized On-Resistance vs. Temperature

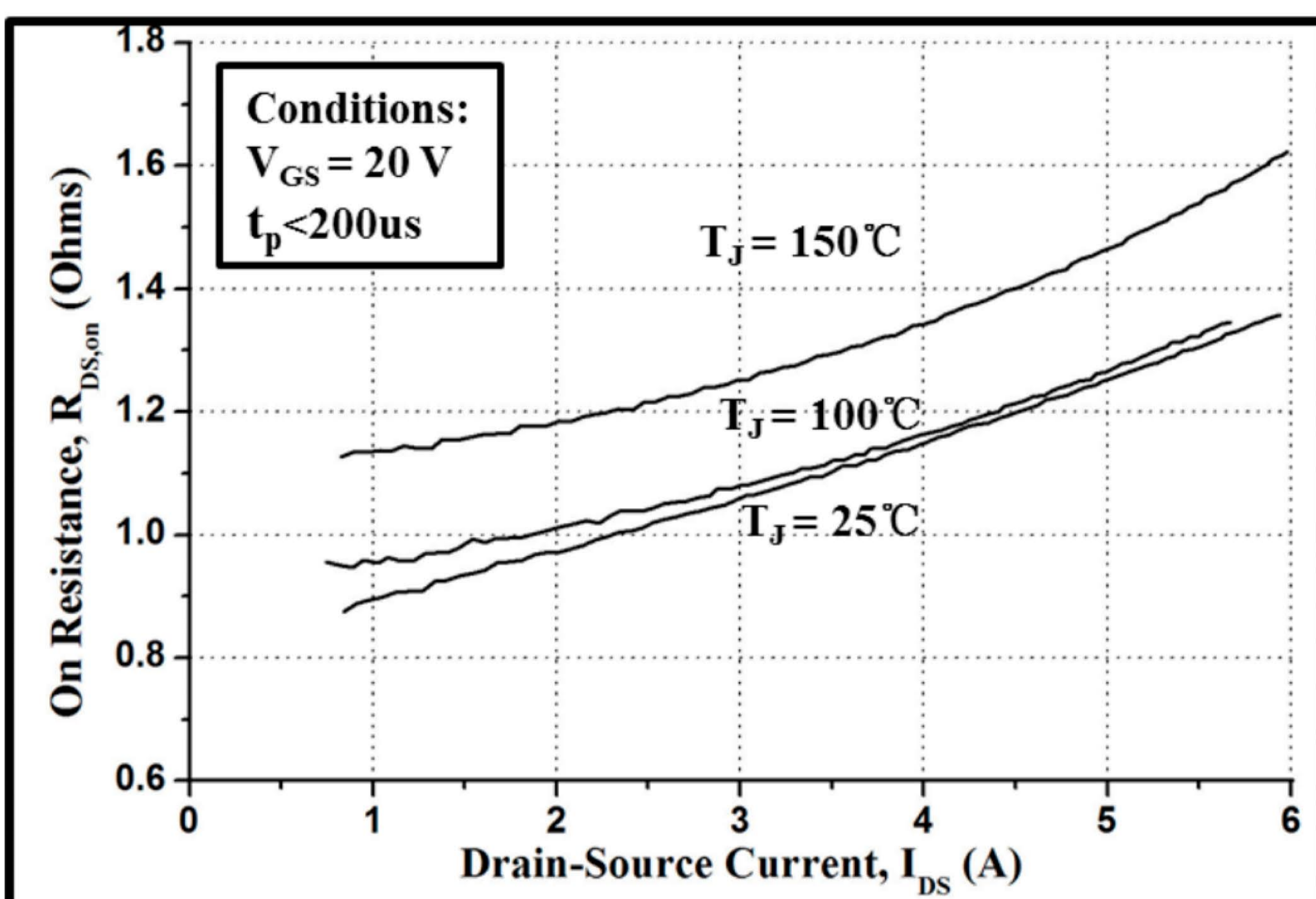


Figure 5. On-Resistance vs. Drain Current

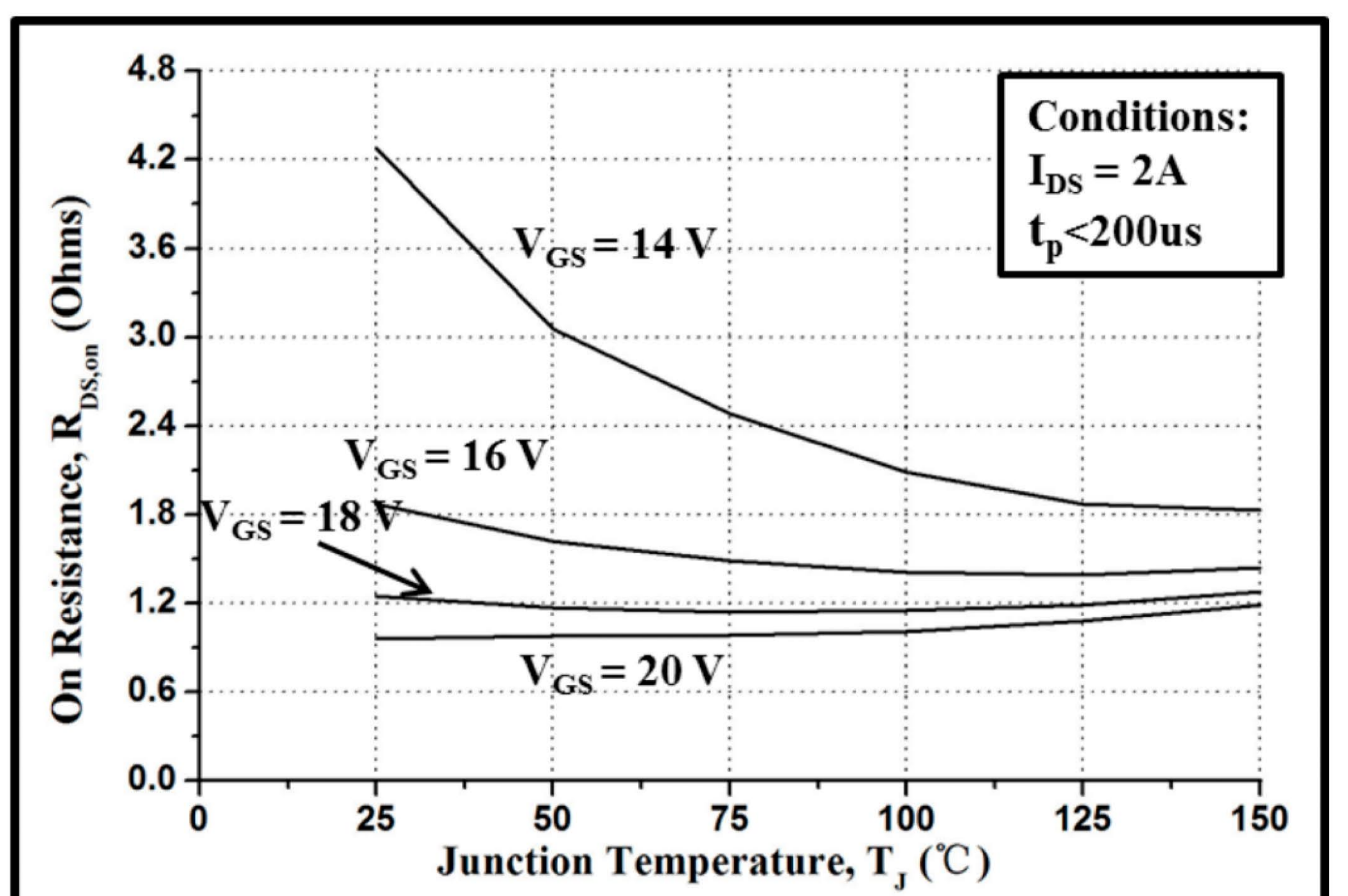


Figure 6. On-Resistance vs. Temperature

Typical Performance

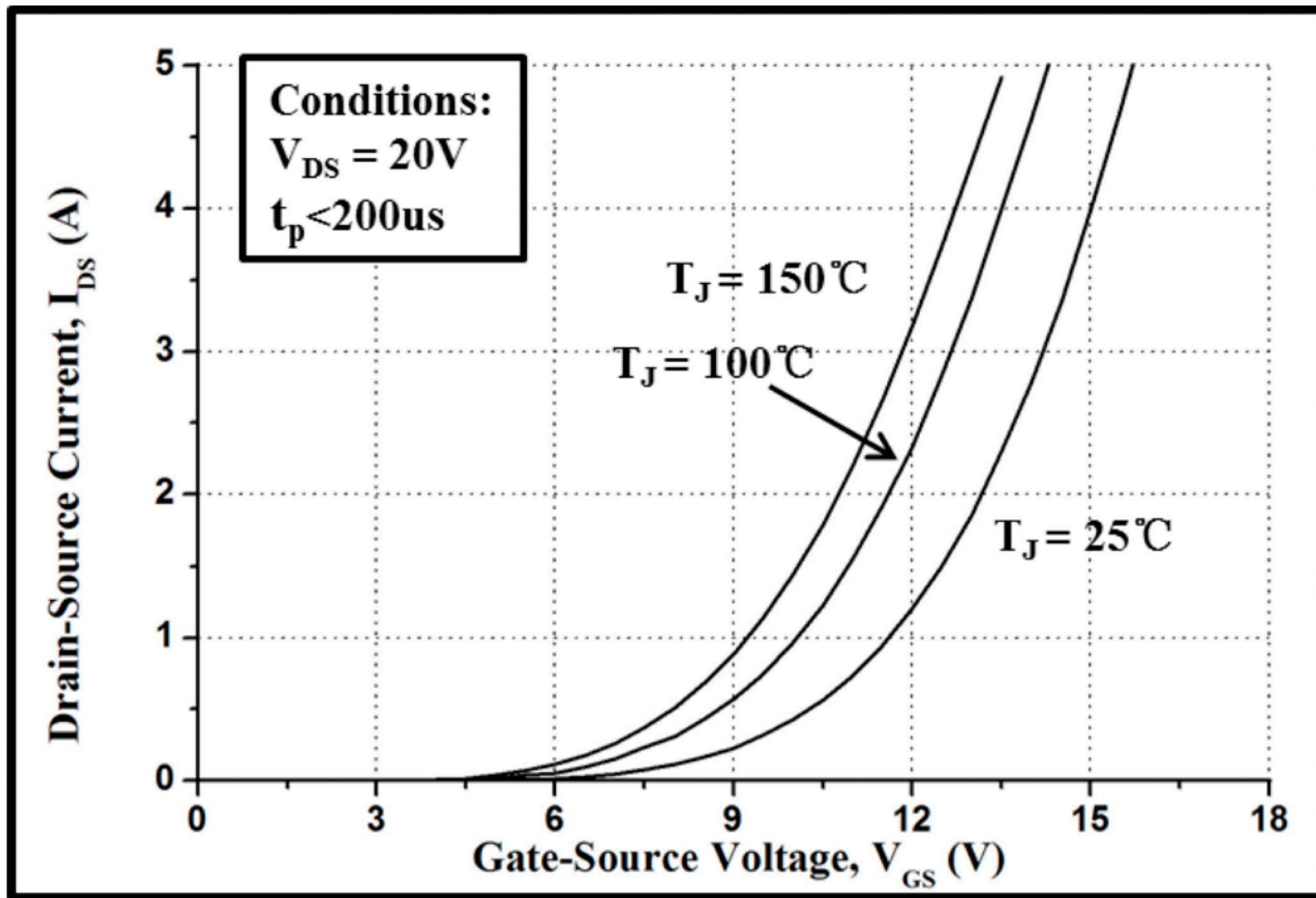


Figure 7. Typical Transfer Characteristics

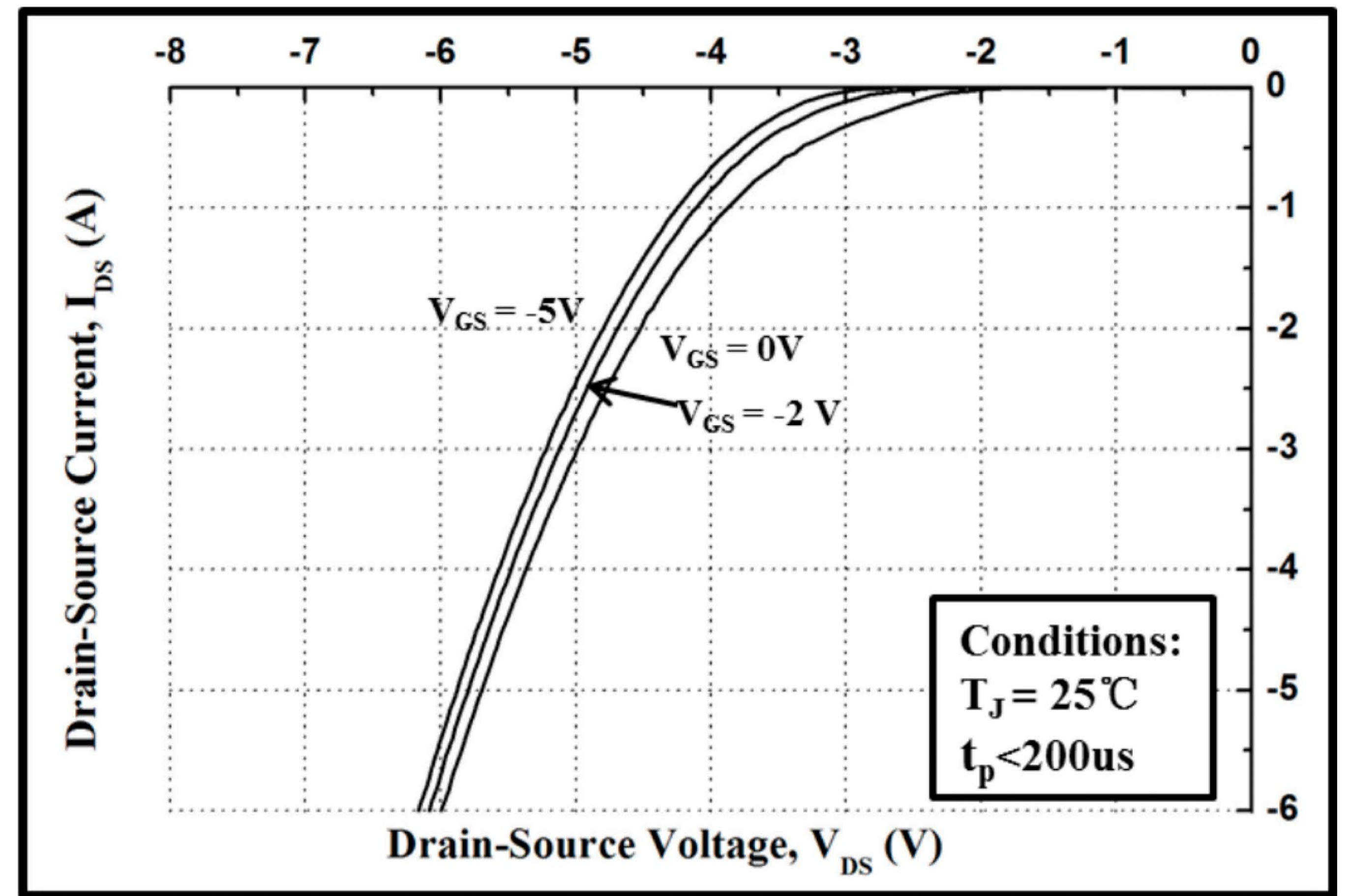


Figure 8. Body Diode Characteristics at 25°C

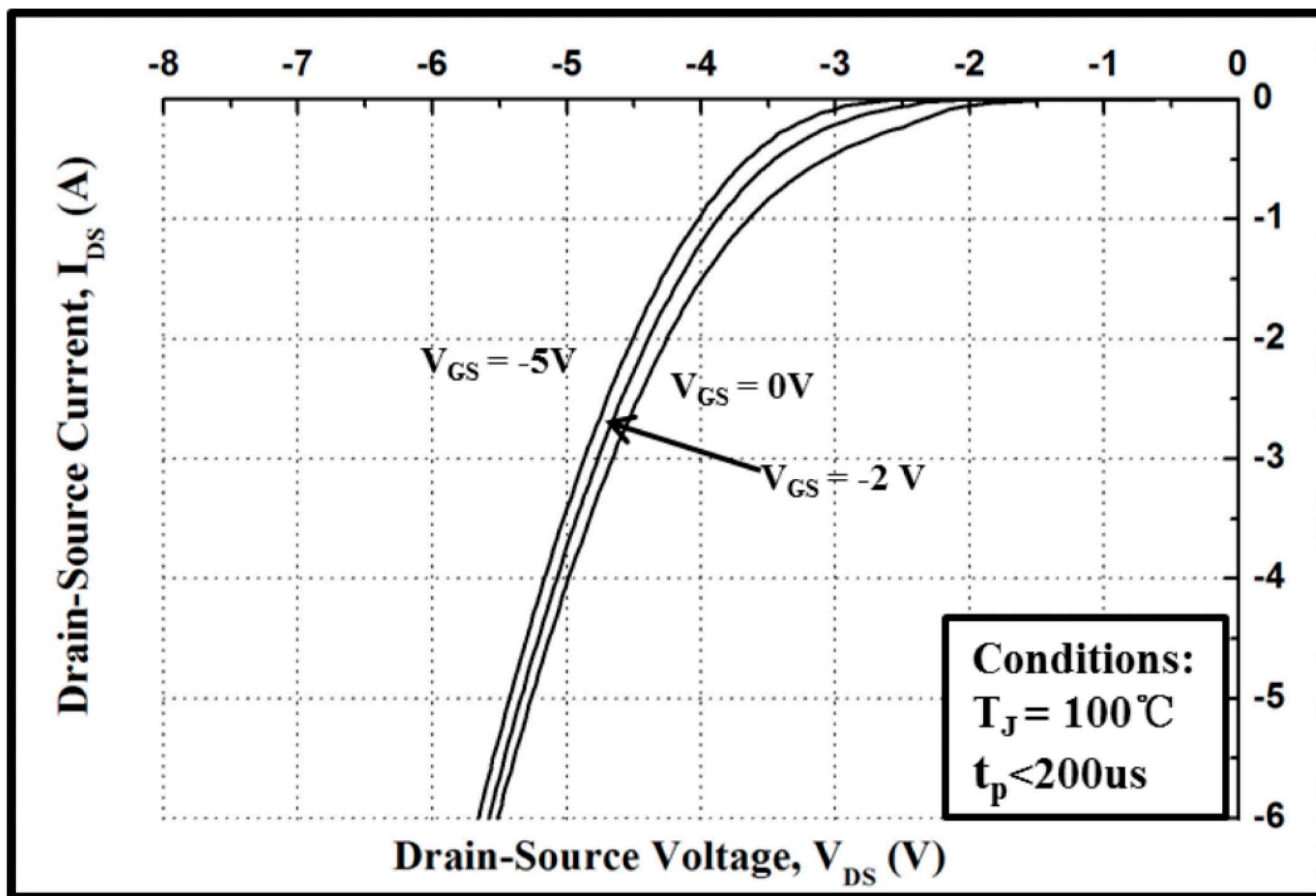


Figure 9. Body Diode Characteristics at 100°C

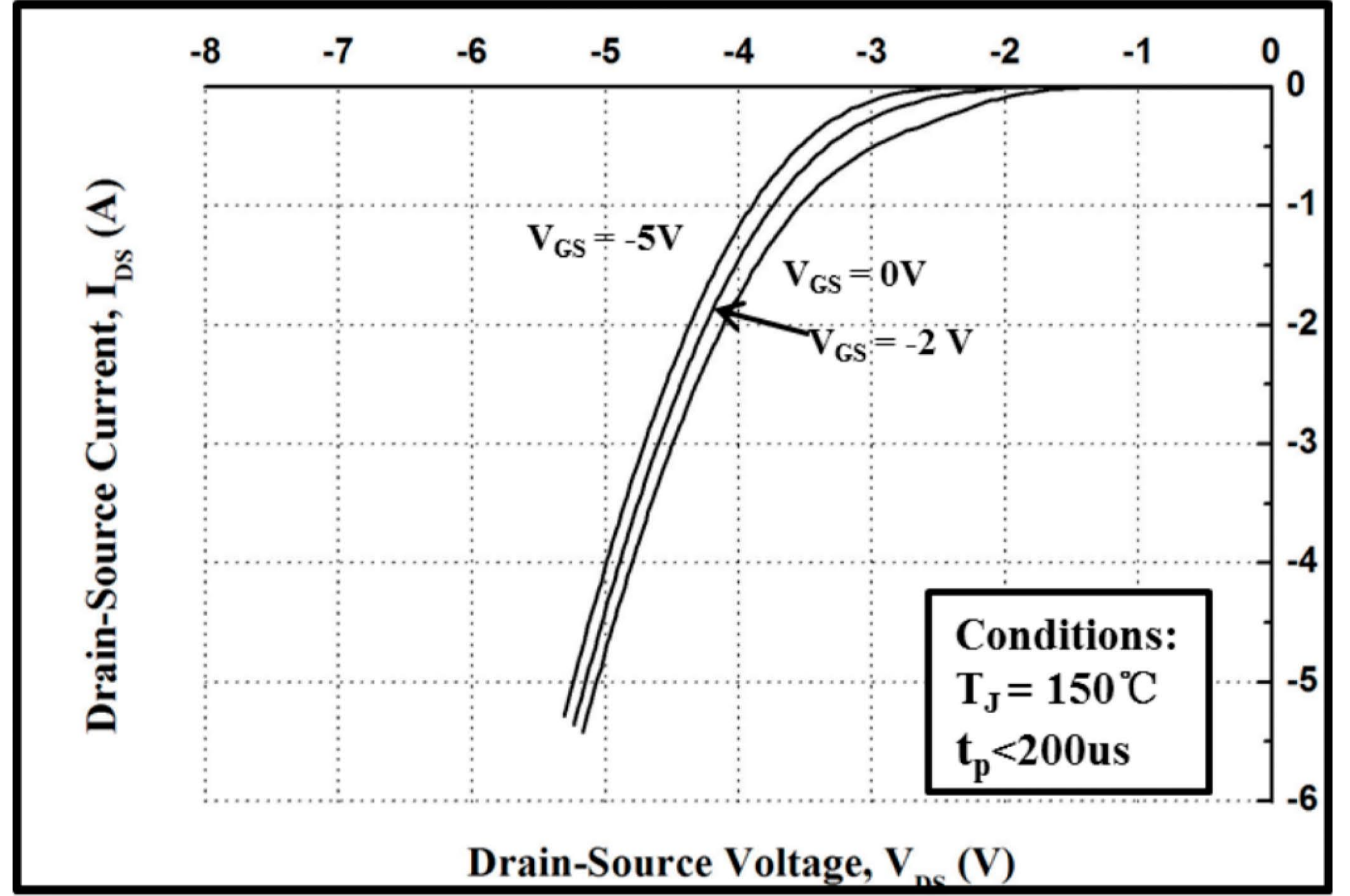


Figure 10. Body Diode Characteristics at 150°C

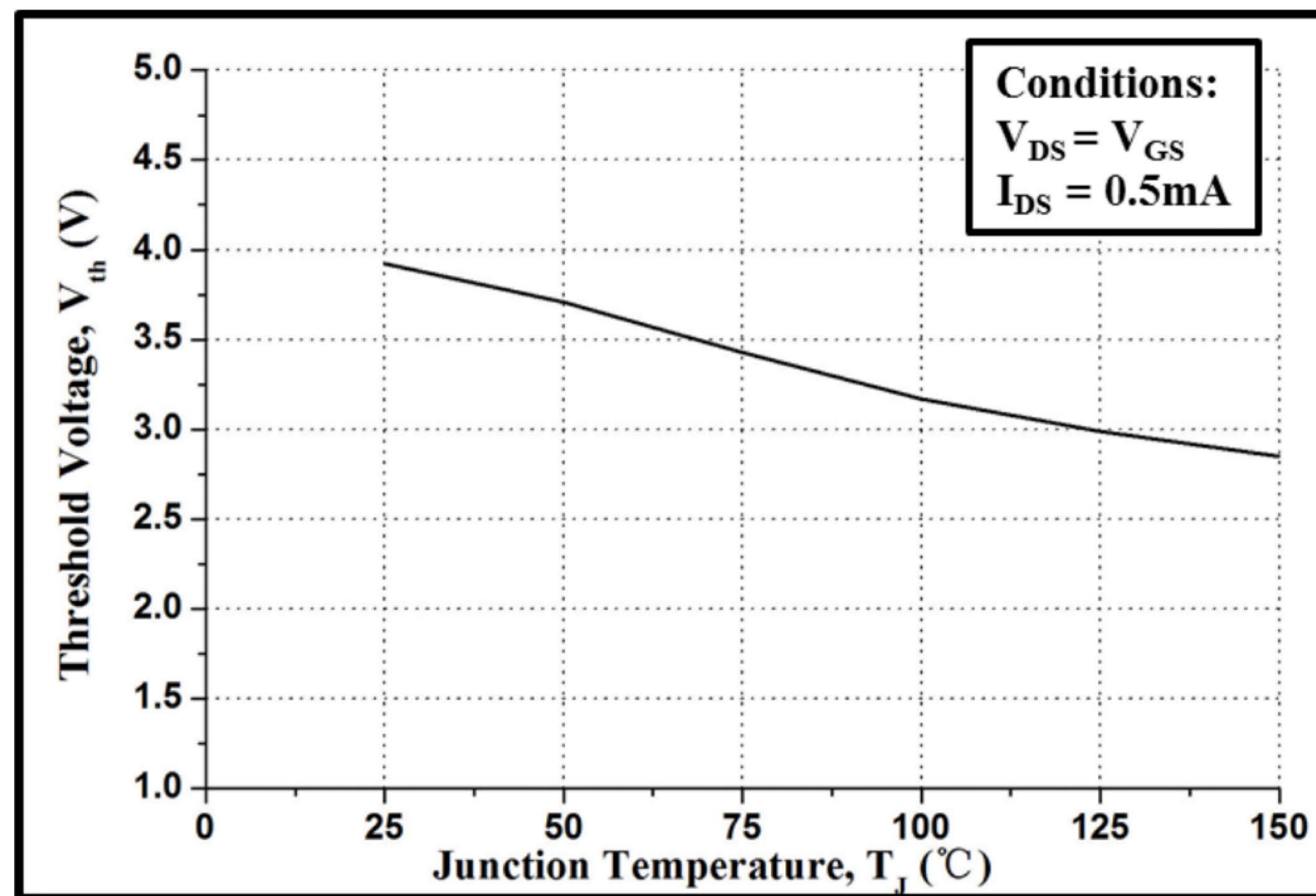


Figure 11. Gate Threshold Voltage vs. Temperature

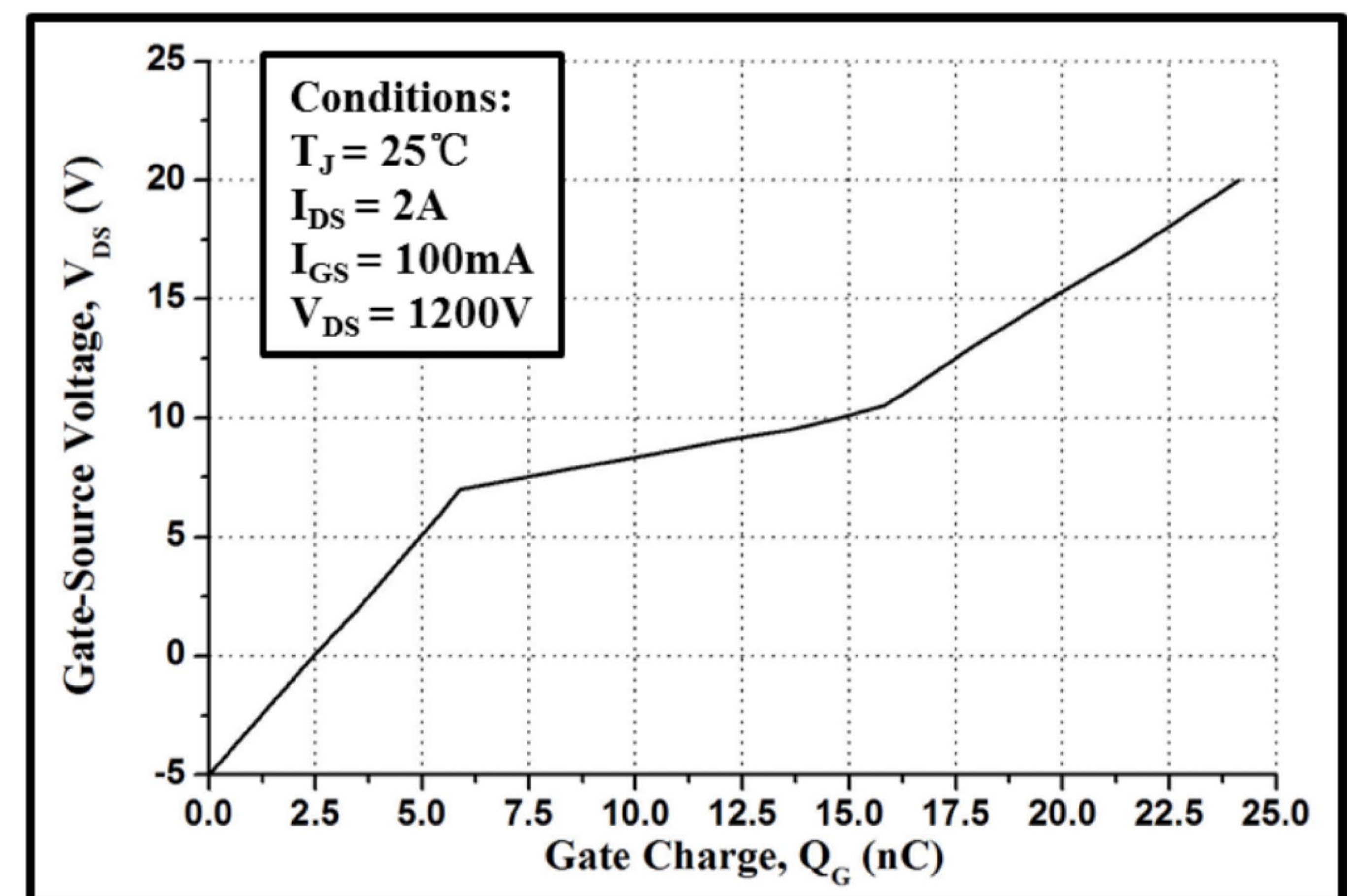


Figure 12. Gate Charge Characteristic

Typical Performance

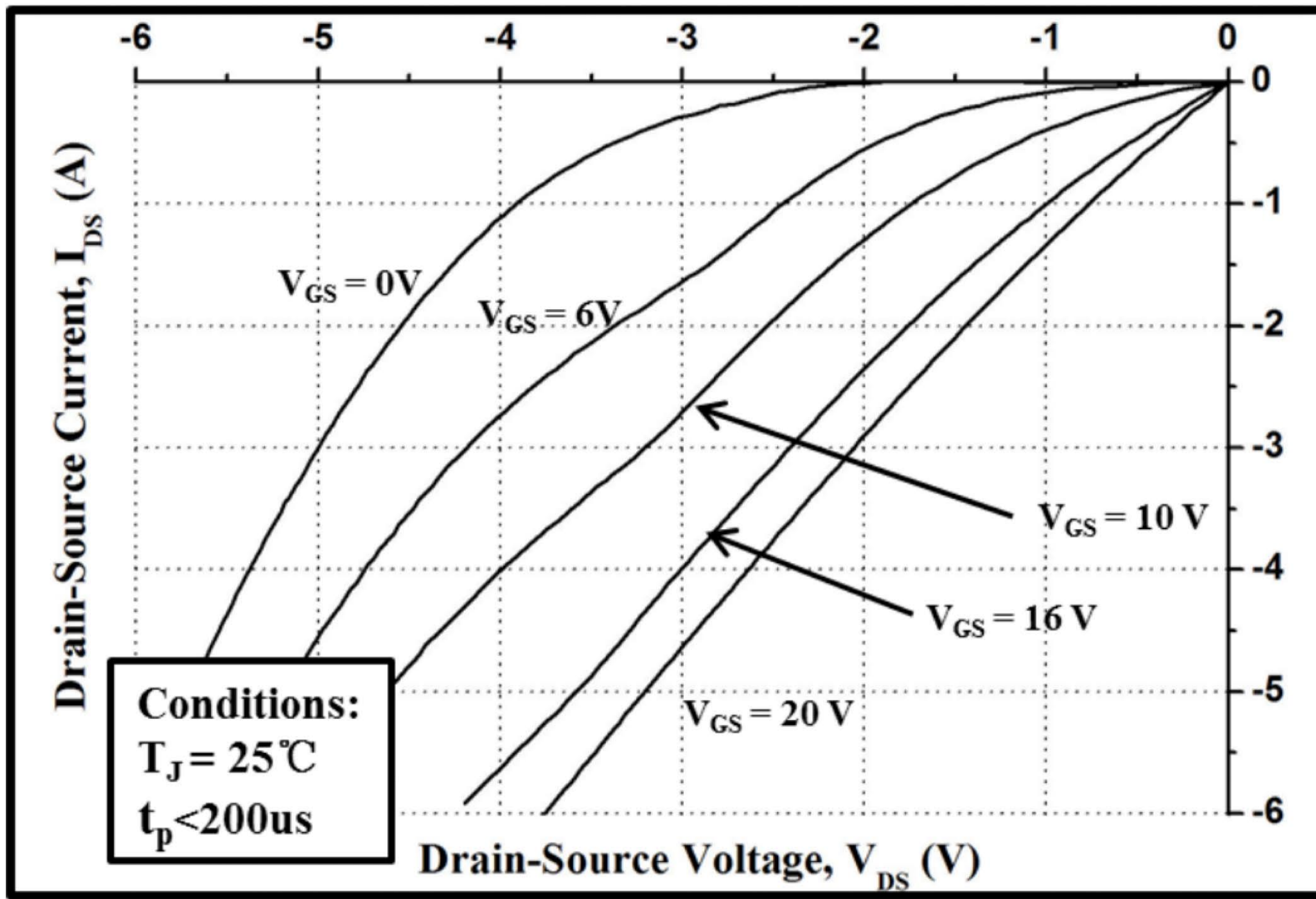


Figure 13. 3rd Quadrant Characteristics at 25°C

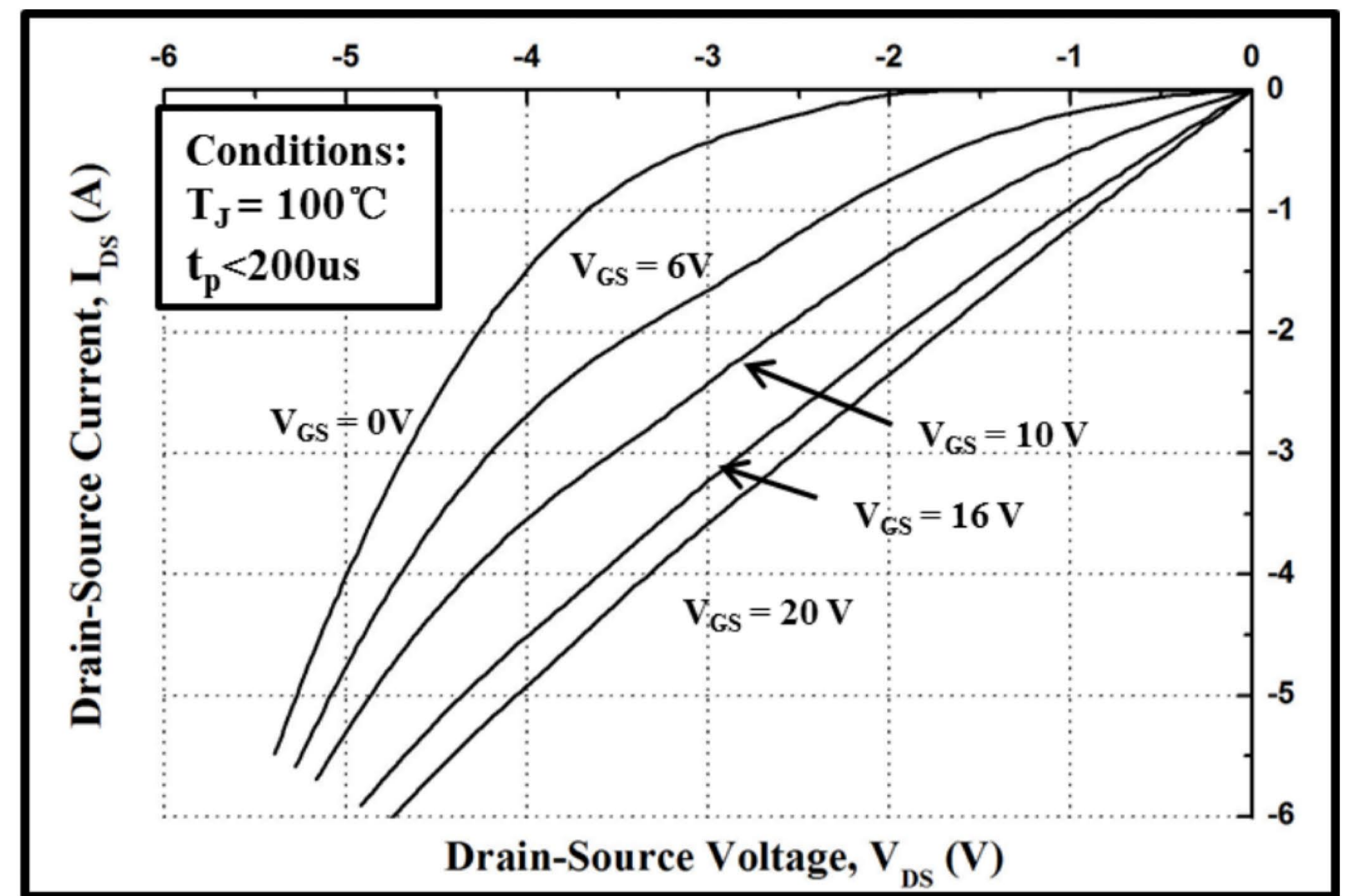


Figure 14. 3rd Quadrant Characteristics at 100°C

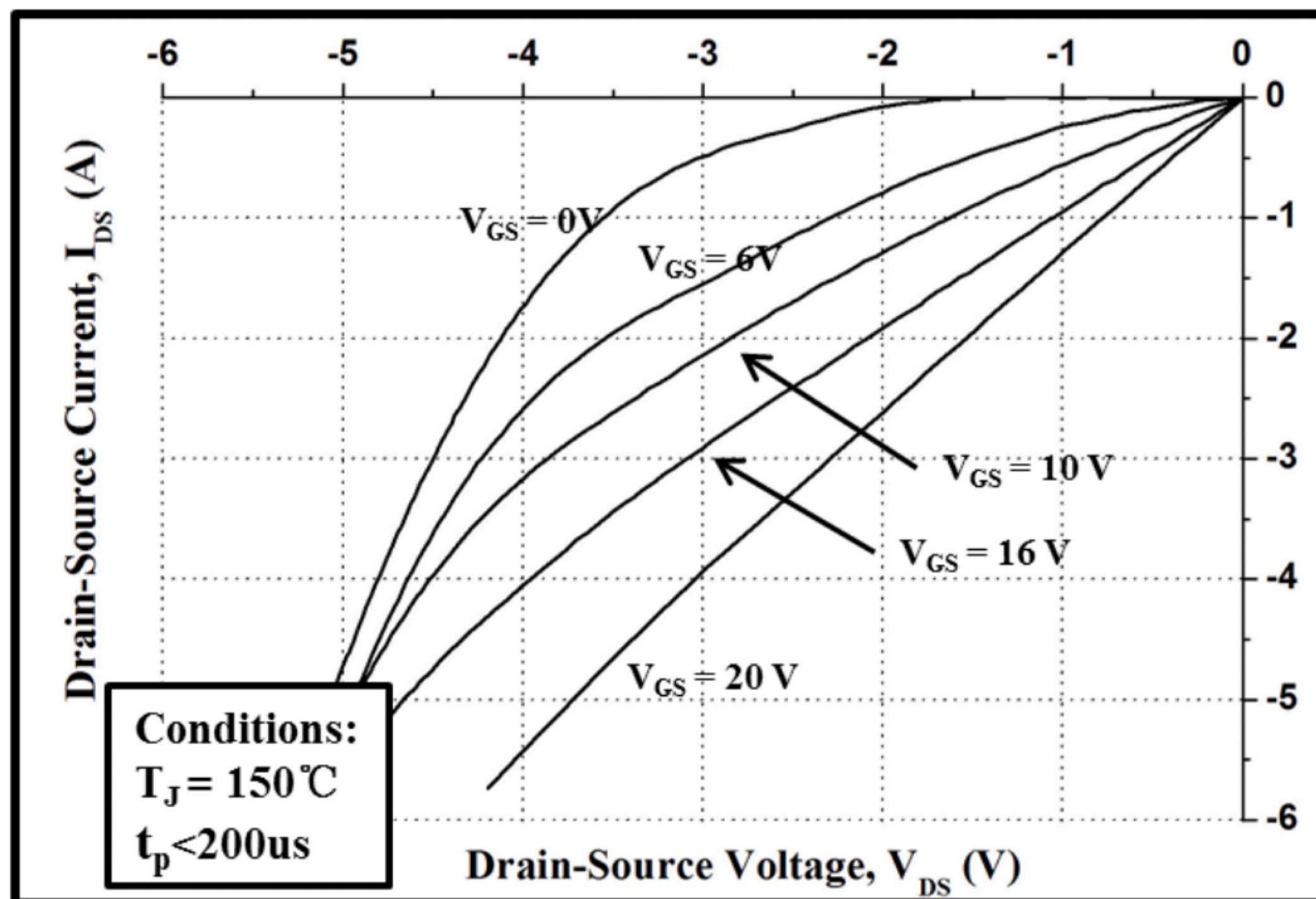


Figure 15. 3rd Quadrant Characteristics at 150°C

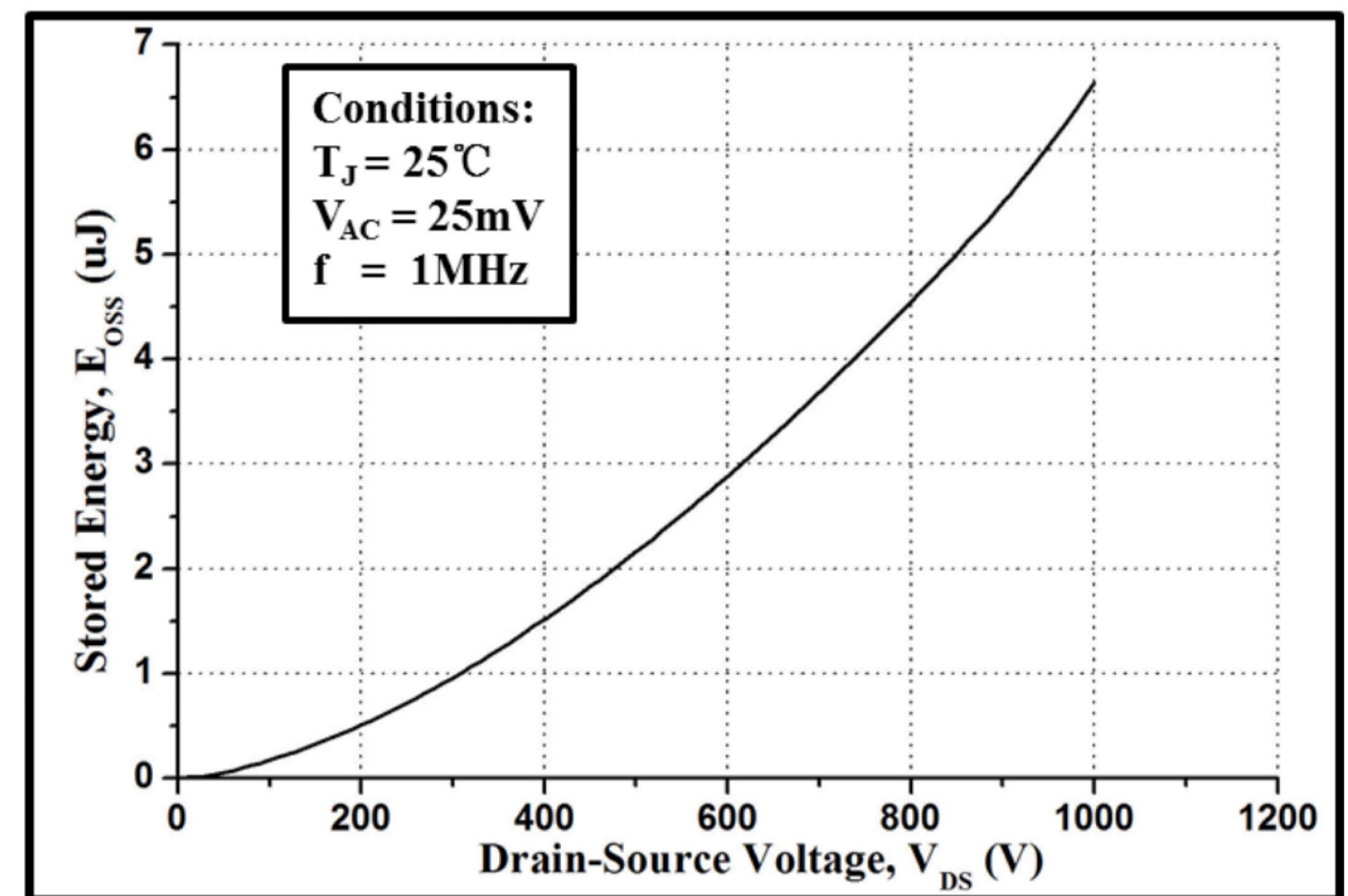


Figure 16. Output Capacitor Stored Energy

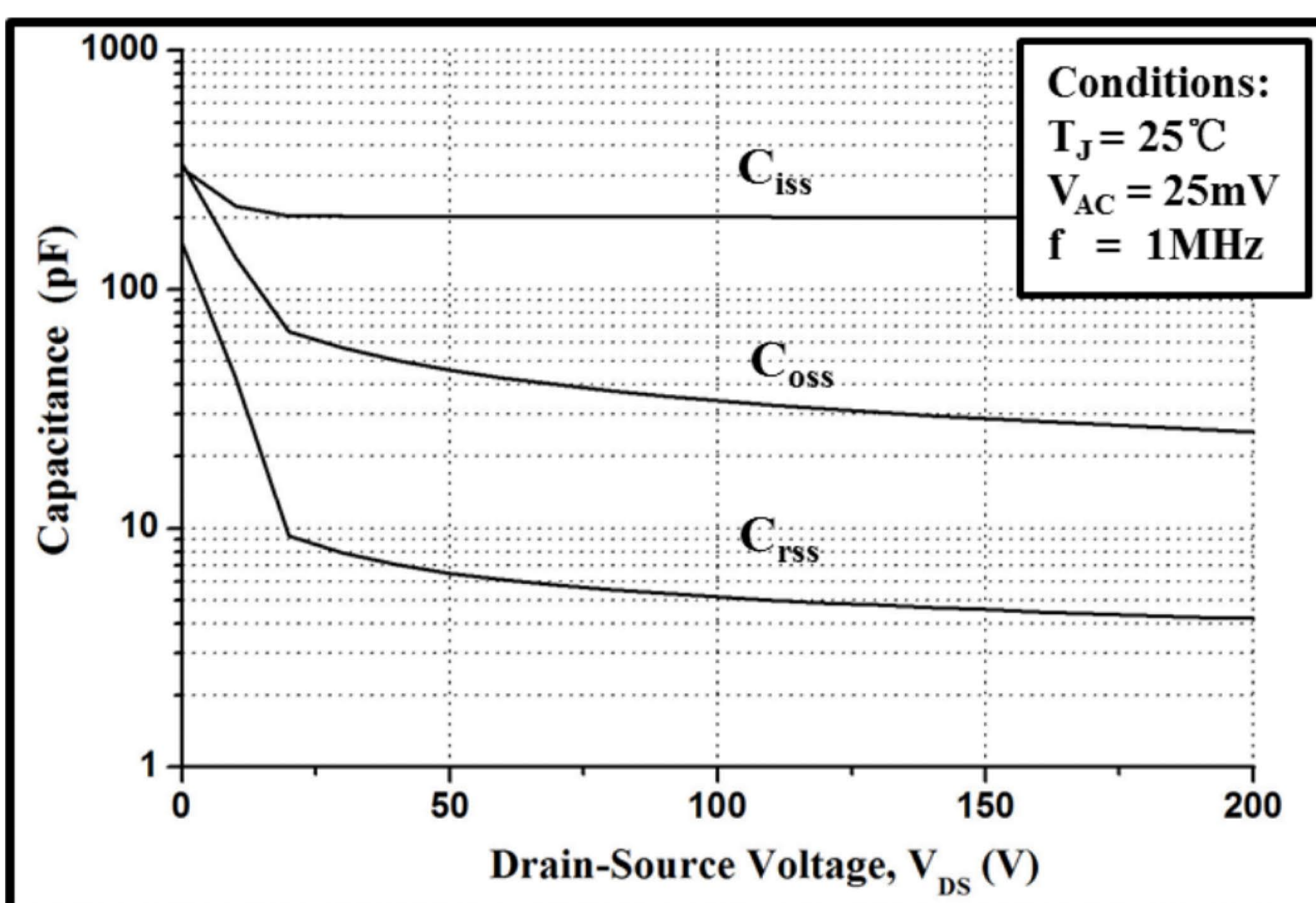


Figure 17. Capacitances vs. Drain-Source Voltage

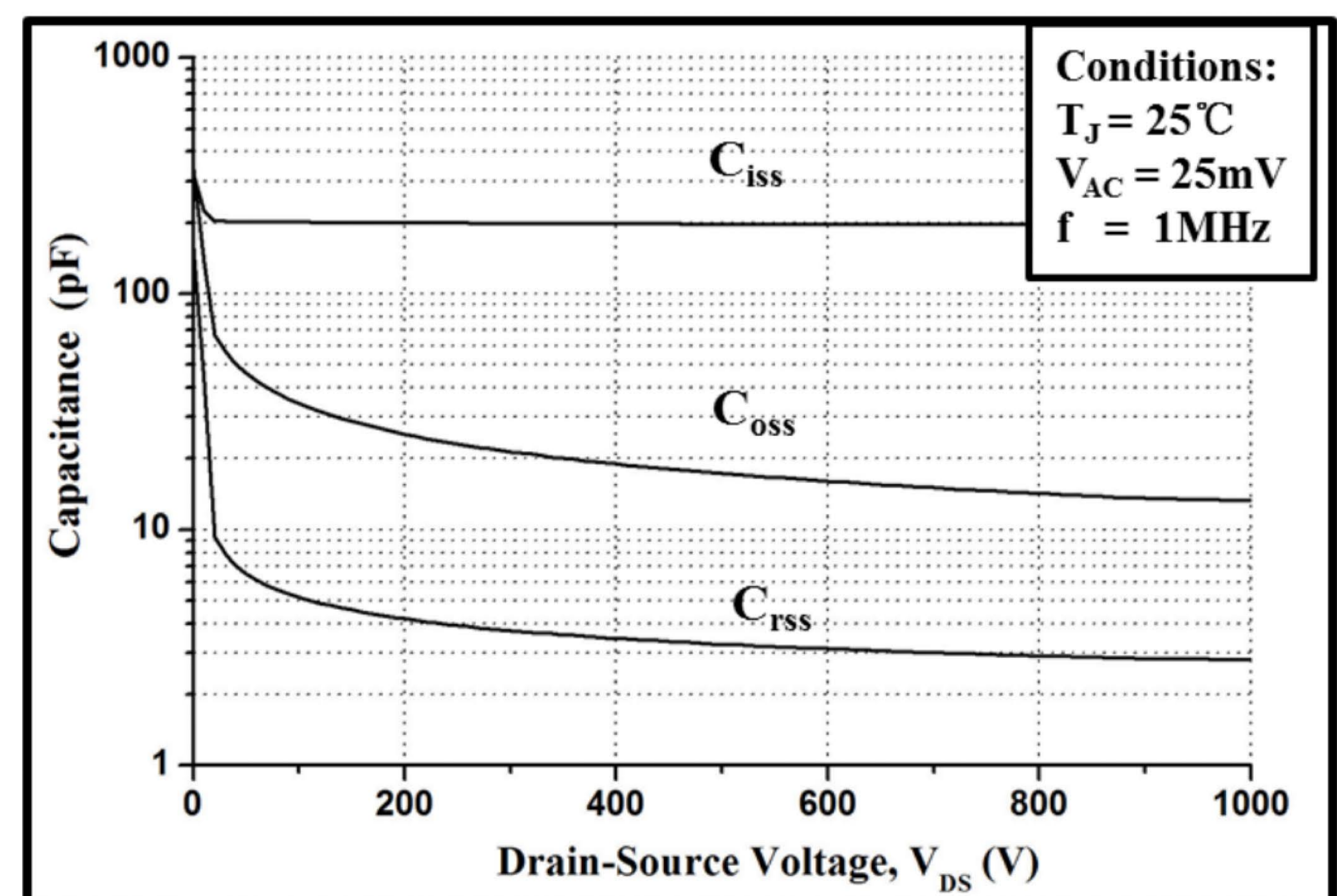


Figure 18. Capacitances vs. Drain-Source Voltage